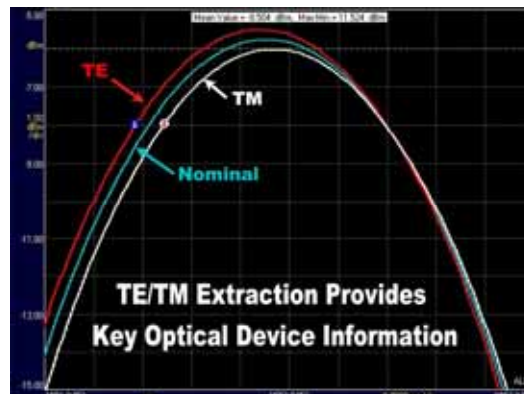


New Technique Gives Insight on Polarization Dependency

Boulder, Colorado – June 16, 2005 – A new and innovative approach for fully characterizing the polarization dependency of polarization-sensitive optical devices was announced today by dBm Optics, Inc. This new technique allows the very rapid extraction of the spectra corresponding to the TE- and TM-incident Stokes vectors from a fast matrix PDL measurement.



“This new technology eliminates the need for any manual calibrations while a user is measuring the TE and TM spectra of their devices,” said Michael Minneman, president of dBm Optics, Inc. “Using the Component Spectrum Analyzer[®] (CSA), our method takes advantage of the Mueller Matrix calculations to extract the TE and TM information on the fly. Full wavelength dependence of the TE state and the TM state are displayed in conjunction with the insertion loss and PDL profiles. Polarization dependence of the bandwidth and center wavelength are also displayed automatically. This represents a true breakthrough in measurement technology.”

“One of the unique applications of this licensed technology is the ability to extract orthogonal spectra for future improvements of device performance by design teams,” explained Michael Crawford, Applications Manager at dBm Optics. “In addition, fabrication teams and assembly teams can monitor the impact of different processes on the TE- and TM-incident spectra throughout the production line. Component suppliers can dramatically reduce testing costs and turnaround time using this technology.”

This new technique is especially valuable when testing planar optical devices, such as AWG multiplexers, ROADMs, wavelength switches, planar splitters and WDMs. This new technique is invaluable for both R&D and volume testing. The technology is already being used for both die and fully-packaged fiber attached devices. The technology can be applied to either 4-state or the higher accuracy 6-state matrix PDL measurement that is fully supported in the dBm Optics Model 2004 Component Spectrum Analyzer[®] (CSA), the Model 4650 Swept Spectrometer, or the Model 4600 PDL Meter.

About dBm Optics. dBm Optics provides accurate, high-speed test equipment for R&D and testing optical components and subsystems. dBm’s advanced instrumentation is used worldwide for R&D, production, high-speed alignment, inspection, and education.

Price, Availability, and for More Information. Available immediately. For pricing or additional information, contact dBm Optics at 1-800-944-7885 (toll-free in the U.S.), at 303-464-1919, or e-mail info@dbmoptics.com. Readers also can access information through the company's Website at www.dbmoptics.com.

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